Se	arch	Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination
10/791,446	LEENERTS ET AL.
Examiner	Art Unit
Khanh V. Nguyen	2817

SEARCHED				
Class	Subclass	Date	Examiner	
330	10, first 400 patents	05/18/05	NKV	
330	297, first 400 patents	05/18/05	NKV	
•				
-				
,		-		
<u>. </u>			<u> </u>	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	12			
	rch History ntout	11/05/05	NKV	

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	11/05/05	NKV
	·	*
	y.	4
		-